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Lim et al.

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(54) **FINGERPRINT SENSOR PACKAGE AND SMART CARD HAVING THE SAME**

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(57) **ABSTRACT**

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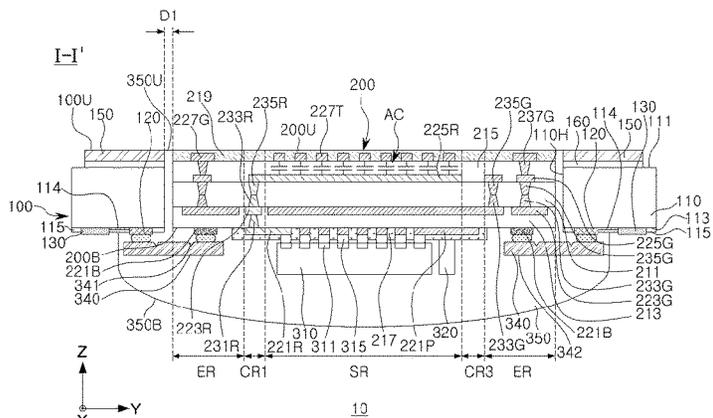
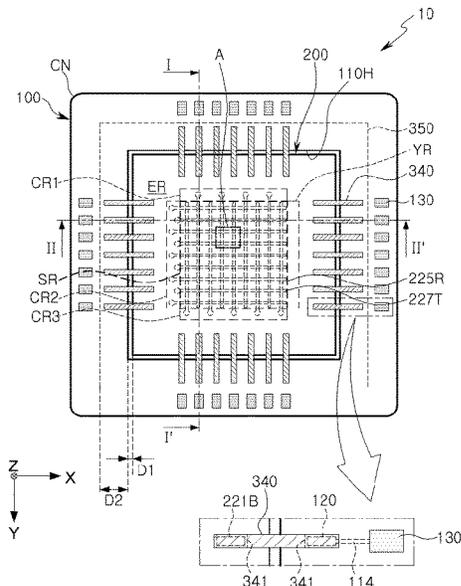
A fingerprint sensor package includes: a first substrate including a core insulating layer including a first surface and a second surface and a through-hole, a first bonding pad on the second surface, and an external connection pad between an edge of the second surface and the first bonding pad; a second substrate in the through-hole and including a third surface and a fourth surface, and including first sensing patterns on the third surface, spaced apart in a first direction, and extending in a second direction, second sensing patterns spaced apart from each other in the second direction and extending in the first direction, and a second bonding pad on the fourth surface; a conductive support electrically connecting the first bonding pad and the second bonding pad and supporting the first substrate and the second substrate; a controller chip on the second substrate; and a molding layer on the second surface.

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H01L 24/40; H01L 24/41; H01L 25/50;

20 Claims, 18 Drawing Sheets



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- (58) **Field of Classification Search**
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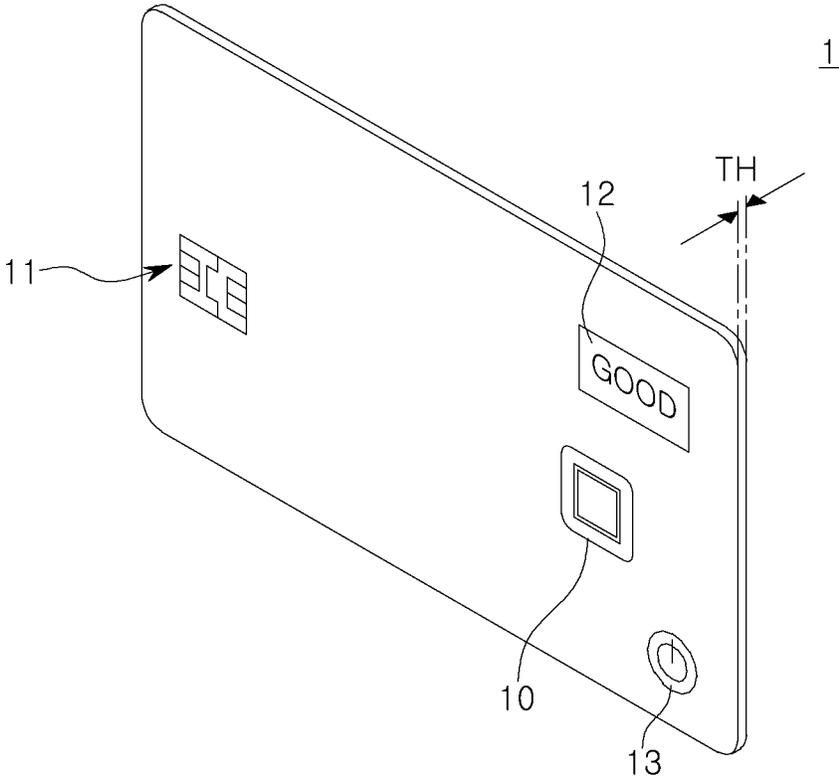


FIG. 1

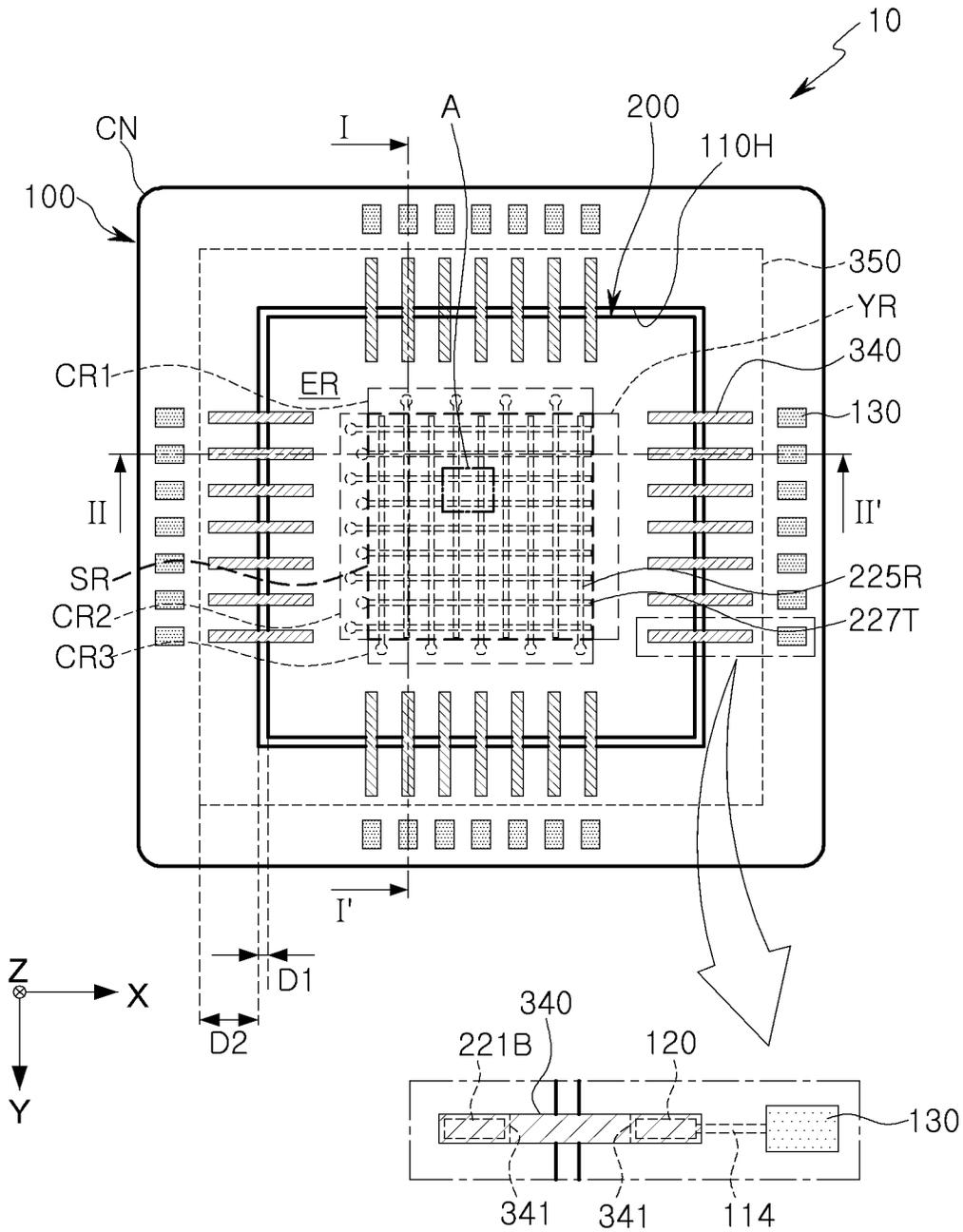


FIG. 2A

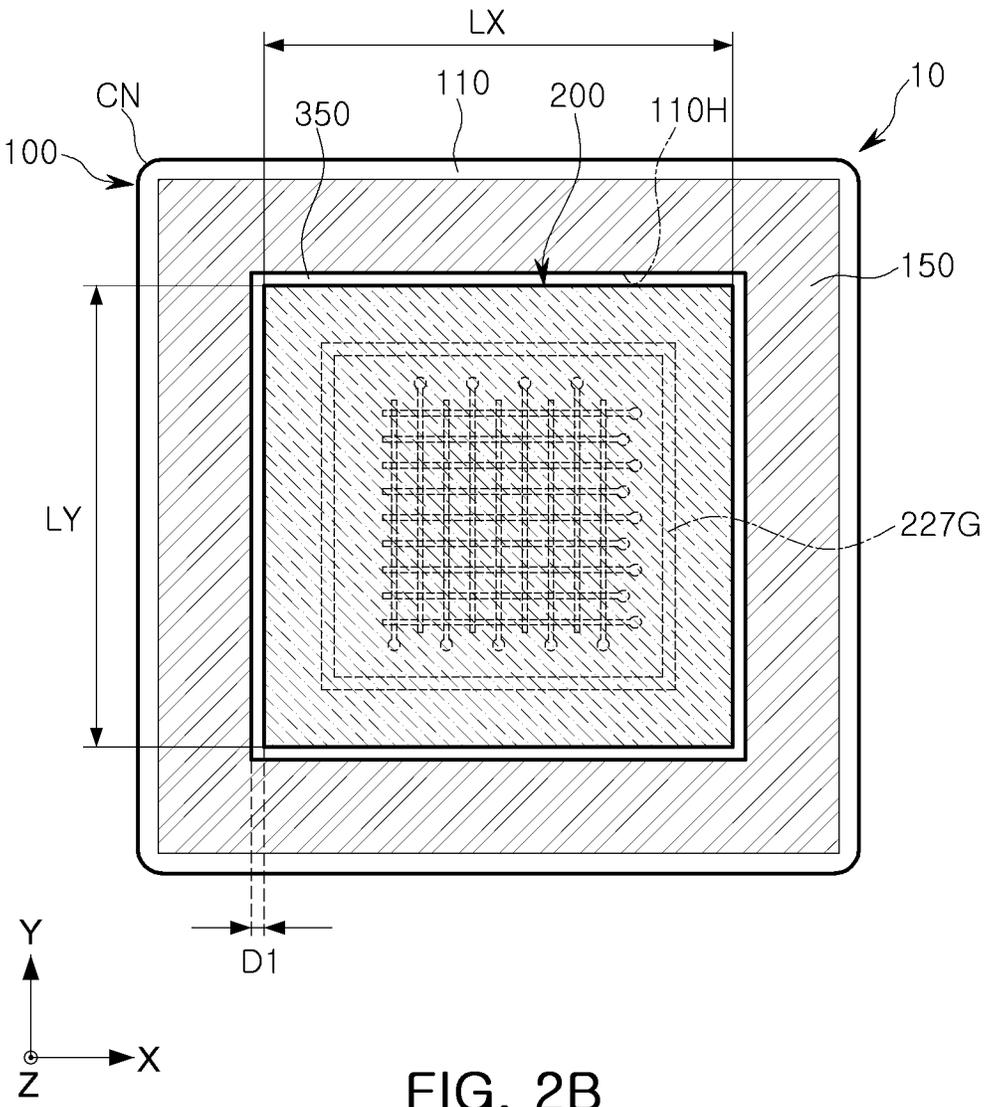


FIG. 2B

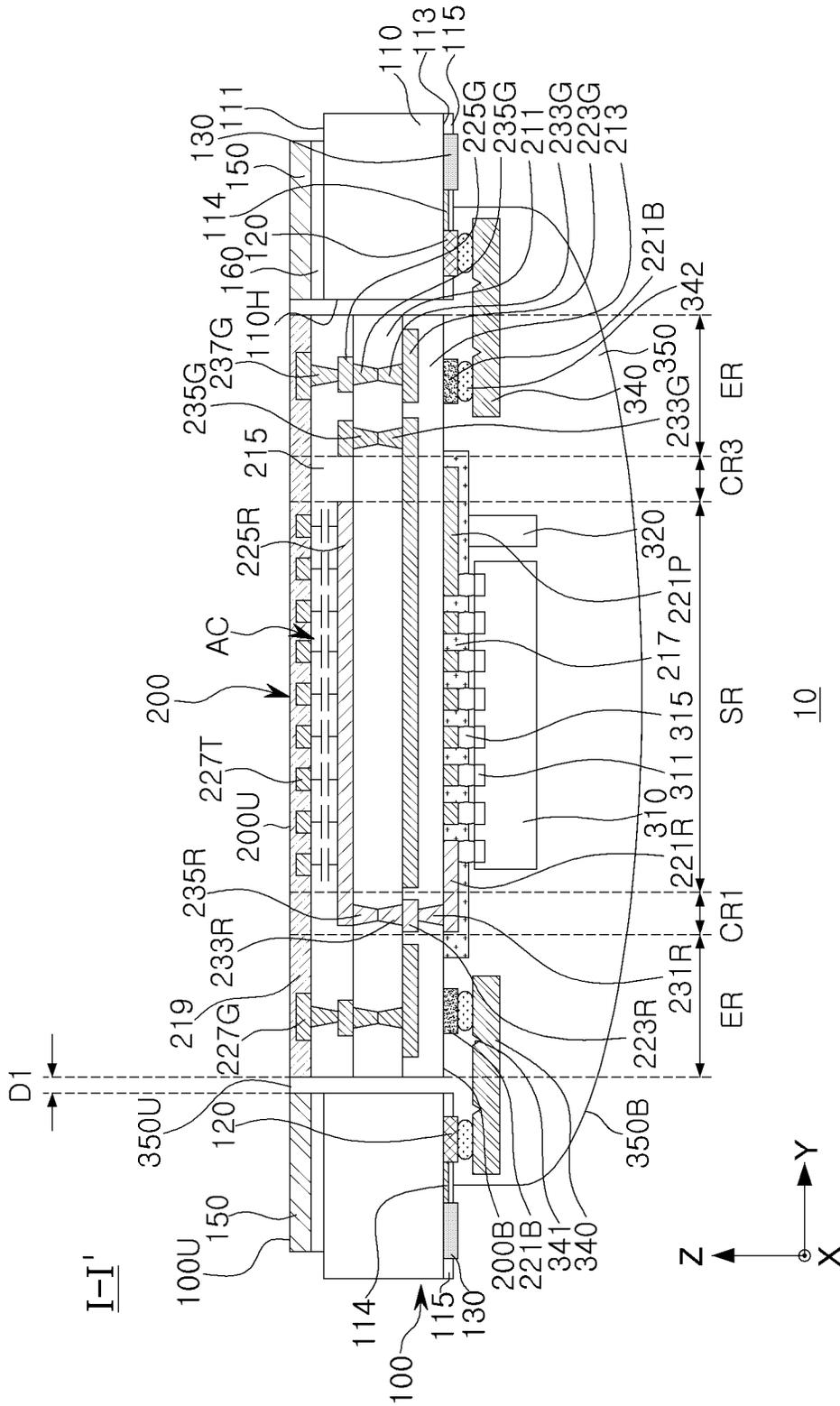


FIG. 2C

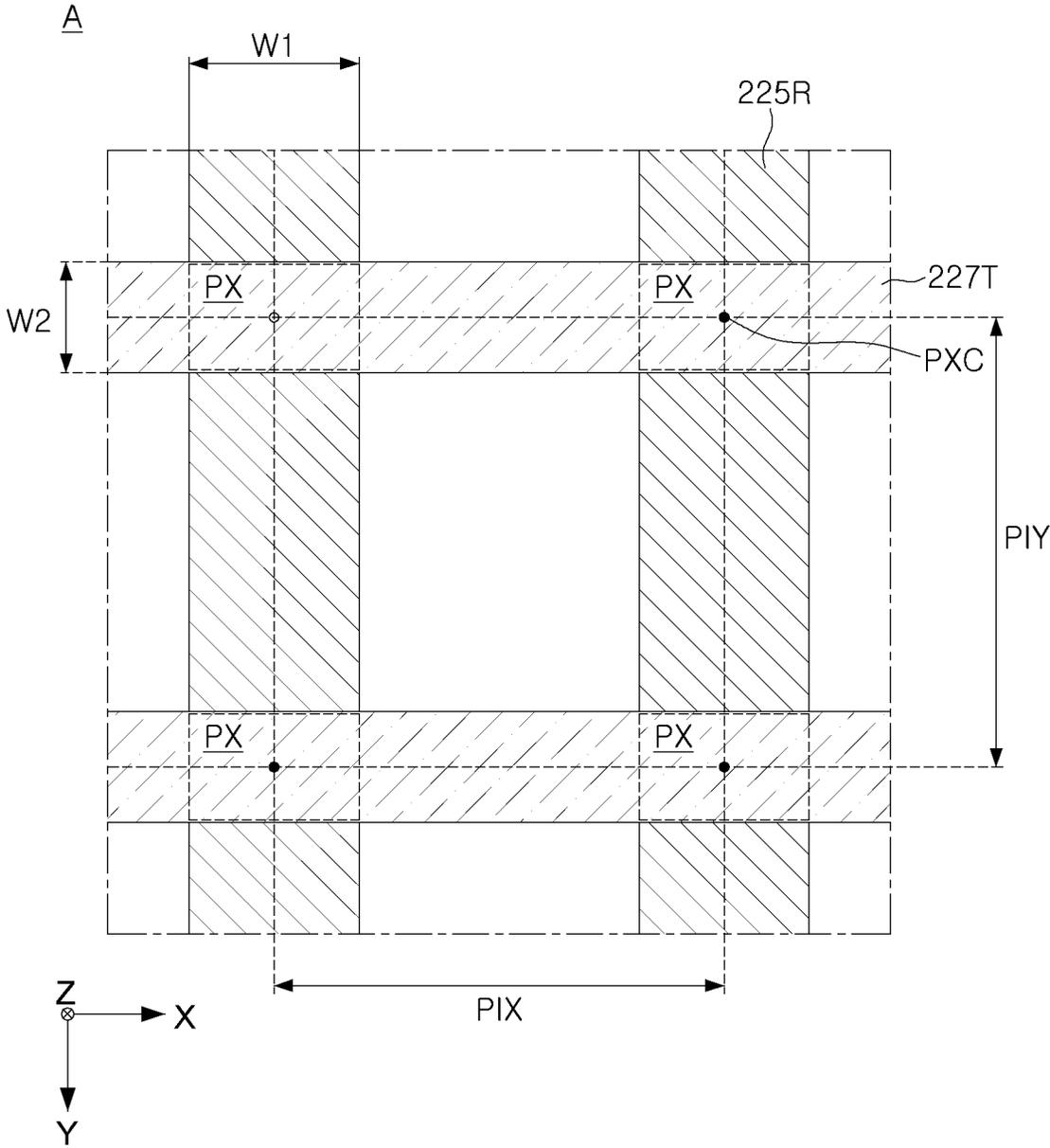


FIG. 2E

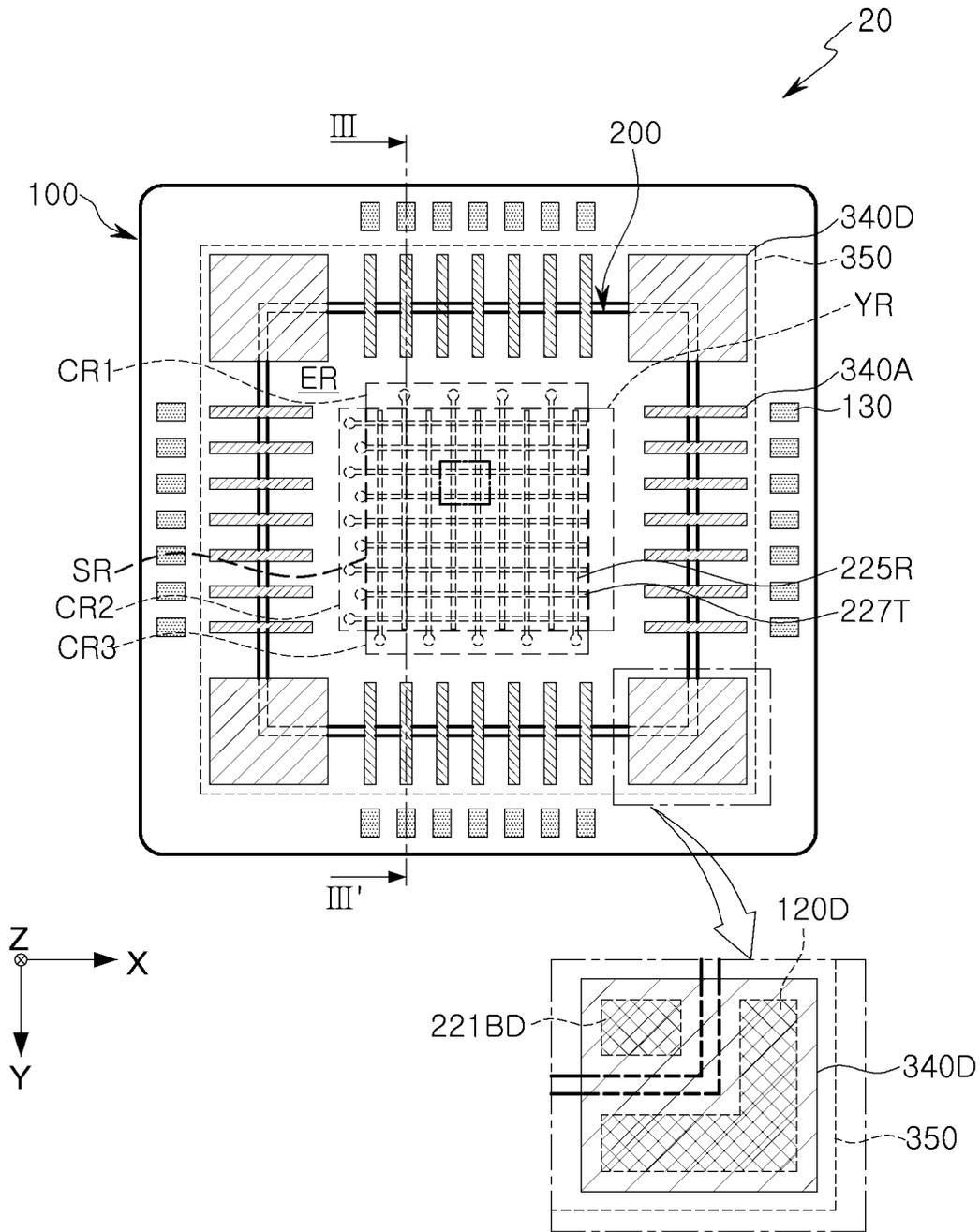


FIG. 3A

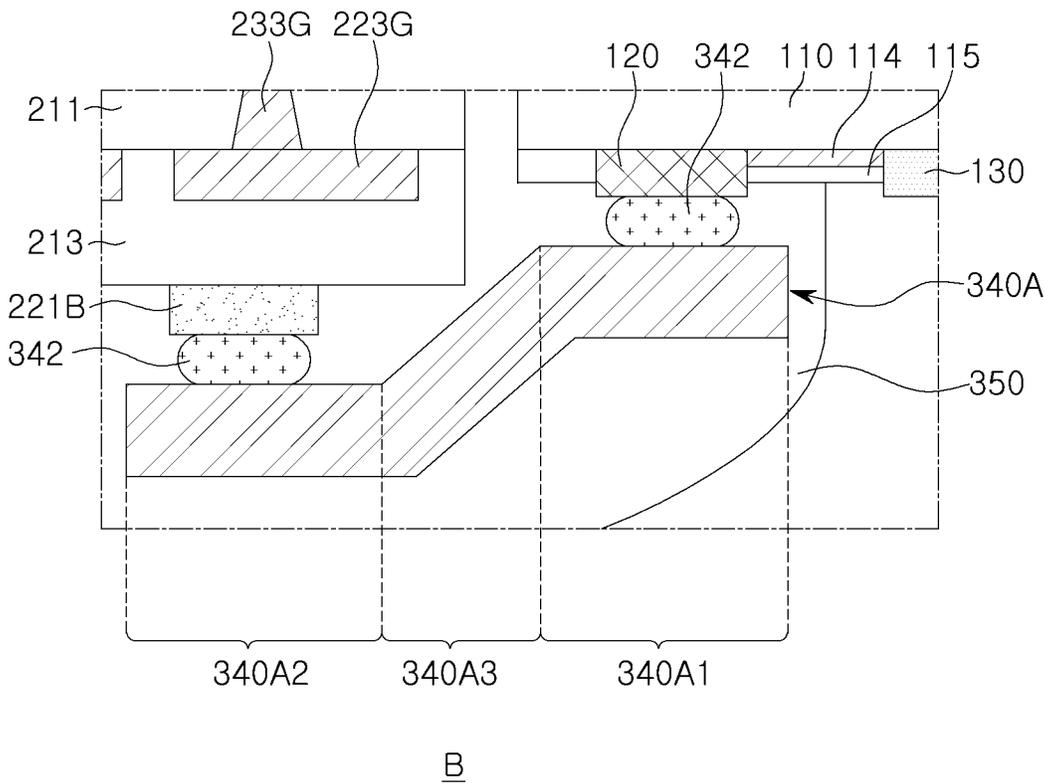


FIG. 3C

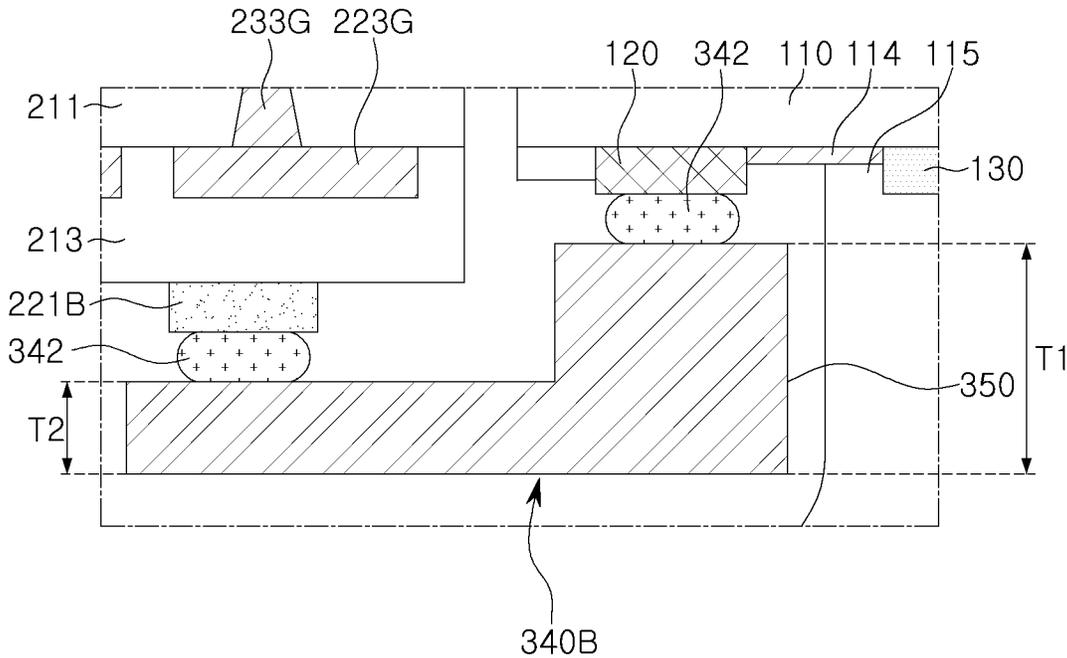


FIG. 4

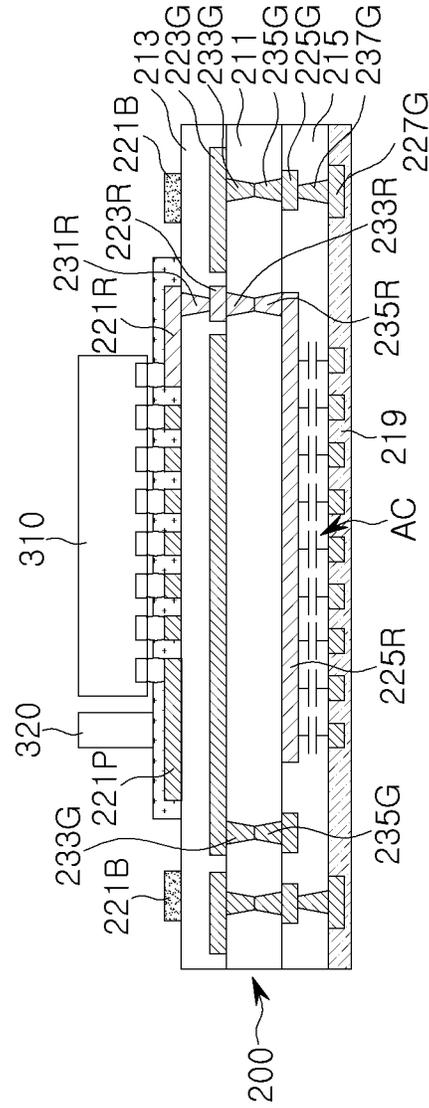


FIG. 5A

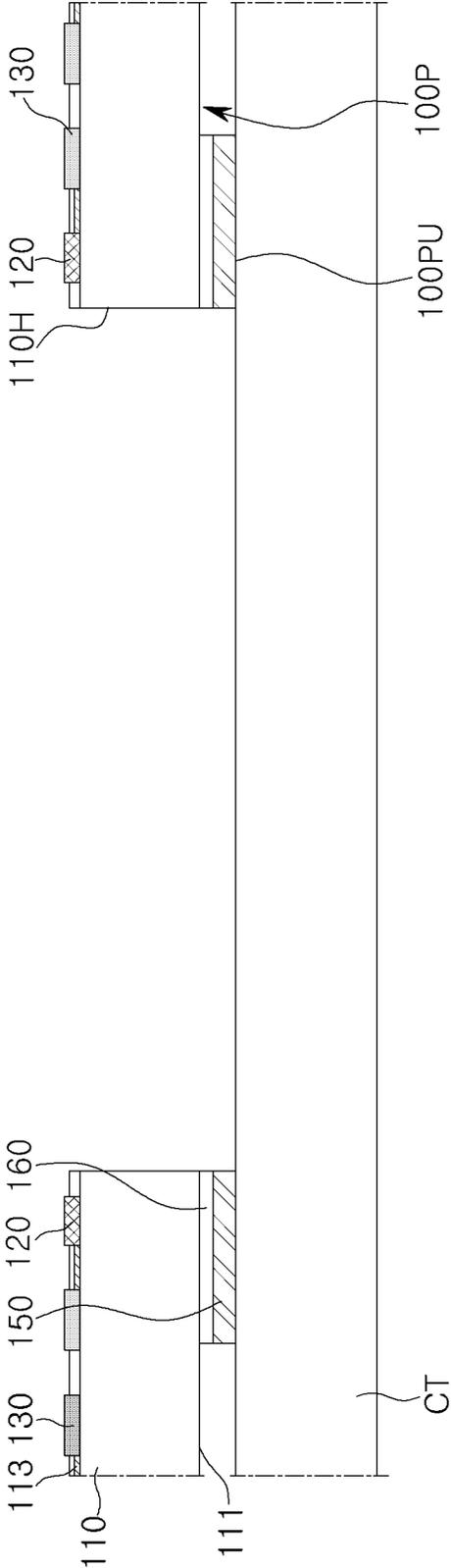


FIG. 5B

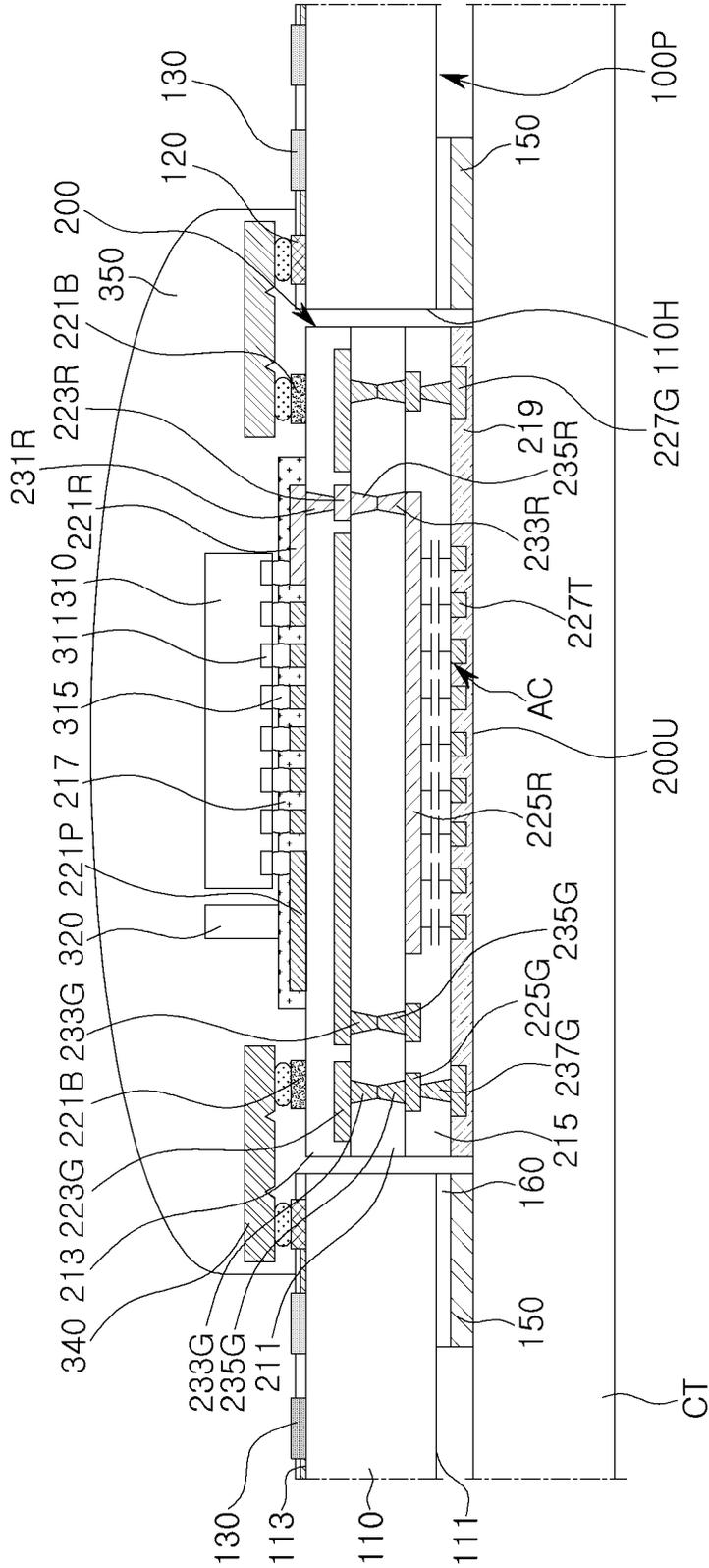


FIG. 5D

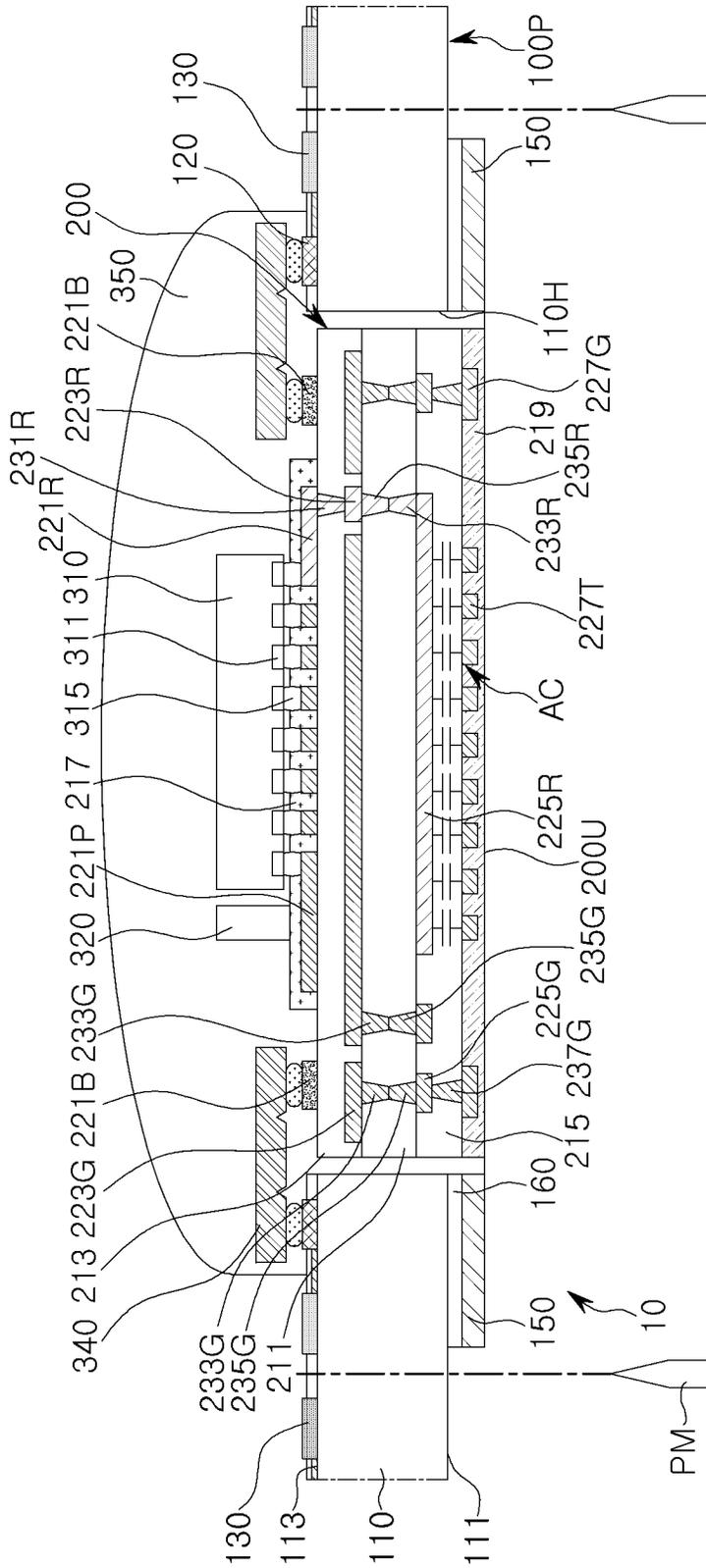


FIG. 5F

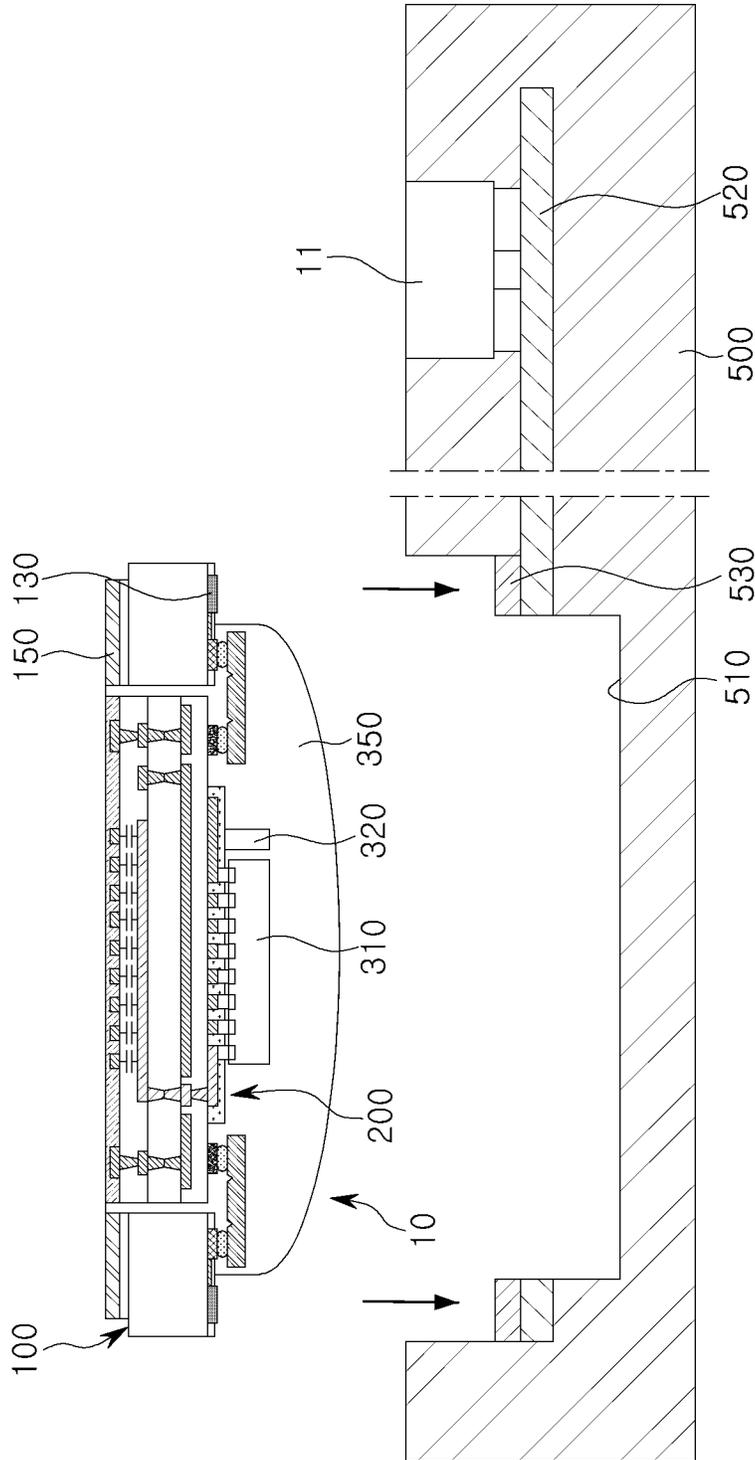


FIG. 5G

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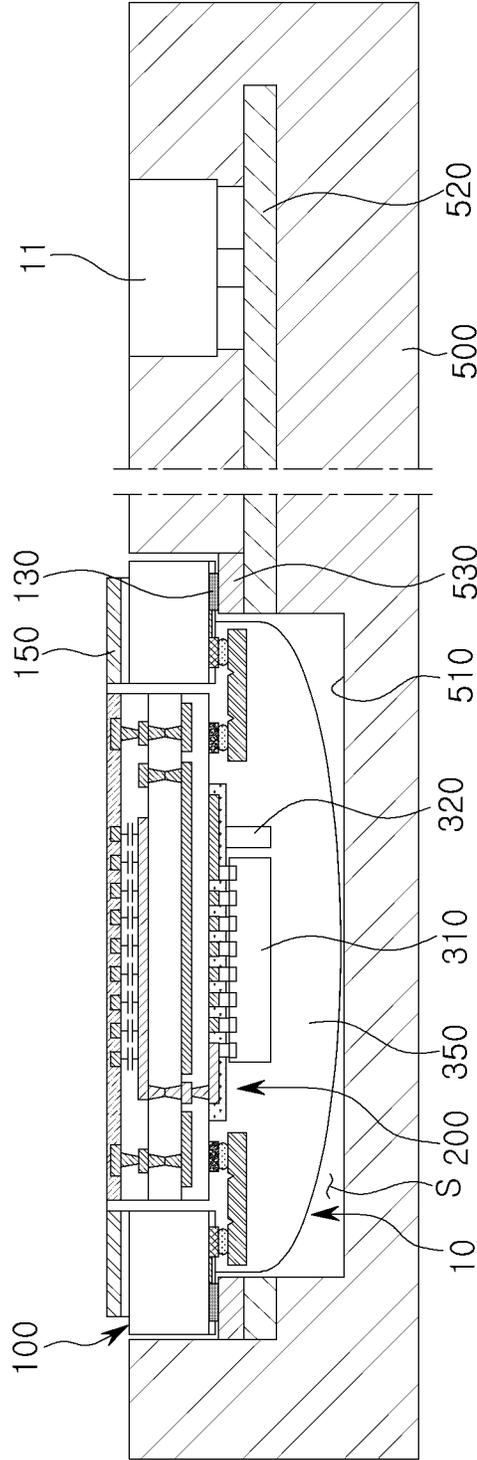


FIG. 5H

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FINGERPRINT SENSOR PACKAGE AND SMART CARD HAVING THE SAME

CROSS-REFERENCE TO RELATED APPLICATION(S)

This application claims benefit of priority to Korean Patent Application No. 10-2022-0121753, filed on Sep. 26, 2022 in the Korean Intellectual Property Office, the disclosure of which is incorporated herein by reference in its entirety.

BACKGROUND

The present inventive concept relates to a fingerprint sensor package and a smart card including the same.

Fingerprint recognition technology may be used to prevent various security accidents by recognizing a user's fingerprint to undergo registration and authentication procedures. In particular, fingerprint recognition technology may be applied to personal and organizational network defense, protection of various contents and data, safe access to financial information, or the like. A fingerprint sensor may obtain user's fingerprint information using an optical method, a capacitive method, an ultrasonic method, a thermal sensing method, or the like. A recent trend in the fingerprint sensor industry may be to provide high reliability while continuously miniaturizing and thinning products. Accordingly, a fingerprint sensor package is required to be robust enough to not be damaged even when repeatedly used while improving reliability and sensitivity of acquisition of fingerprint information and reducing overall size and height.

SUMMARY

An aspect of the present inventive concept is to provide a fingerprint sensor package and a smart card including the fingerprint sensor package that are resistant to damage even after repeated use due to improved reliability.

According to an aspect of the present inventive concept, a fingerprint sensor package includes: a first substrate including a core insulating layer including a first surface and an opposite second surface and a through-hole extending through the first and second surfaces, a first bonding pad disposed along a circumference of the through-hole on the second surface of the core insulating layer, and an external connection pad between an edge of the second surface of the core insulating layer and the first bonding pad; a second substrate in the through-hole of the core insulating layer and including a third surface and an opposite fourth surface, the second substrate including a plurality of first sensing patterns on the third surface, spaced apart in a first direction and extending in a second direction intersecting the first direction, a plurality of second sensing patterns spaced apart from each other in the second direction and extending in the first direction, and a second bonding pad on the fourth surface; a conductive support electrically connecting the first bonding pad and the second bonding pad and supporting the first substrate and the second substrate; a controller chip on the second substrate; and a molding layer on the second surface of the core insulating layer, at least partially filling the through-hole between the first substrate and the second substrate, covering at least a portion of the second substrate and the first bonding pad, and spaced apart from the external connection pad.

According to an aspect of the present inventive concept, a fingerprint sensor package includes: a first substrate

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including a core insulating layer including a first surface and an opposite second surface, the first substrate including a through-hole, a first bonding pad extending along a circumference of the through-hole on the second surface, and an external connection pad on an edge of the second surface; a second substrate including a third surface including a sensing region and a peripheral region surrounding the sensing region and a fourth surface opposite to the third surface, and including a second bonding pad extending along an edge of the fourth surface; a conductive support vertically overlapping the first substrate and the second substrate, supporting the first substrate and the second substrate below the first substrate and the second substrate, and electrically connecting the first bonding pad and the second bonding pad to each other; and a controller chip on the fourth surface.

According to an aspect of the present inventive concept, a smart card includes: a card body including a groove region and a contact pad; a security chip in the card body; and a fingerprint sensor package configured to sense a user's fingerprint and transmit a signal for a sensing result to the security chip, wherein the fingerprint sensor package includes: a first substrate including a core insulating layer including a first surface and a second surface, opposite to each other, and having a substantially rectangular or square ring shape with a through-hole passing through the first and second surfaces, a first bonding pad disposed along a circumference of the through-hole on the second surface of the core insulating layer, and an external connection pad between an edge of the second surface of the core insulating layer and the first bonding pad; a second substrate in the through-hole of the core insulating layer and including a third surface and a fourth surface, opposite to each other, and including a plurality of first sensing patterns spaced apart in a first direction and extending in a second direction, perpendicular to the first direction, a plurality of second sensing patterns spaced apart from each other in the second direction and extending in the first direction, and a second bonding pad; a conductive support electrically connecting the first bonding pad and the second bonding pad and supporting the first substrate and the second substrate; a controller chip on the second substrate; and a molding layer on the second surface of the core insulating layer, filling the through-hole between the first substrate and the second substrate, at least partially covering the second substrate and the first bonding pad, and spaced apart from the external connection pad.

BRIEF DESCRIPTION OF DRAWINGS

The above and other aspects, features, and advantages of the present inventive concept will be more clearly understood from the following detailed description, taken in conjunction with the accompanying drawings, in which:

FIG. 1 is a schematic perspective view illustrating a smart card according to an embodiment.

FIGS. 2A to 2E are views illustrating a fingerprint sensor package according to an embodiment.

FIGS. 3A to 3C are views illustrating a fingerprint sensor package according to an embodiment.

FIG. 4 is a cross-sectional view illustrating a modified example of the conductive support illustrated in FIG. 3C.

FIGS. 5A to 5H are views illustrating a method of manufacturing a smart card in a process sequence according to an embodiment.

DETAILED DESCRIPTION

FIG. 1 is a schematic perspective view illustrating a smart card 1 according to an embodiment.

Referring to FIG. 1, a smart card **1** may include a fingerprint sensor package **10**, a security chip **11**, a display or display unit **12**, and a power actuator such as a power button **13**.

The smart card **1** may further include information displayed on a conventional credit card or a conventional debit card, such as a card number identification or card number identification unit, an expiration date identification or expiration date identification unit, a user name, or the like. According to embodiments, the smart card **1** may further include an RF chip.

When a user brings his or her fingerprint into contact with a fingerprint sensor, the fingerprint sensor package **10** may recognize a contacted fingerprint. The fingerprint sensor package **10** may compare a recognized fingerprint and a registered fingerprint to determine whether the recognized fingerprint matches the registered fingerprint. The fingerprint sensor package **10** may operate after the smart card **1** is turned on.

The security chip **11** may store encrypted financial information. When the recognized fingerprint and the registered fingerprint match, the security chip **11** may grant payment authority to the user of the smart card **1**. For example, the smart card **1** may prevent a financial accident due to theft or loss by allowing the security chip **11** to authorize the user to pay, based on a recognition result of the fingerprint sensor package **10**.

The display unit **12** may display whether the recognized fingerprint matches the registered fingerprint, whether the smart card **1** is turned on or off, or the like. The display unit **12** may display letters, numbers, special symbols, or the like, and may further include a light emitting unit or light emitter in some cases. Depending on a type of smart card **1**, the display unit **12** may be omitted.

The power button **13** may turn the smart card **1** on or off. The smart card **1** in an off state may be converted to be in an on state by manipulating the power button **13**, and the smart card **1** in an on state may be converted to be in an off state by manipulating the power button **13**. In addition, when a set time elapses after the smart card **1** is converted to be in an on state, the smart card **1** may be automatically converted to be in an off state. Depending on a type of smart card **1**, the power button **13** may be omitted.

In some embodiments, a thickness TH of the smart card **1** may range from about 0.5 mm to about 1 mm. In addition, the thickness TH of the smart card **1** may be about 0.84 mm or less in accordance with international standards. For example, the thickness TH of the smart card **1** may be about 0.76 mm or less.

Since a smart card **1** according to an embodiment may include the fingerprint sensor package **10**, and may have the same thickness as a conventional credit card or a conventional debit card, while maintaining a manner in which the conventional credit card or the conventional debit card is used, a high level of security may be provided to the user. In addition, a shape of a cross-section of the smart card **1** of this embodiment may be substantially identical or similar to that schematically illustrated in FIG. 5H.

FIGS. 2A to 2E are views illustrating a fingerprint sensor package **10** according to an embodiment.

Specifically, FIG. 2A is a bottom view schematically illustrating a layout of some components of a fingerprint sensor package **10**, FIG. 2B is a plan view illustrating the fingerprint sensor package **10** of FIG. 2A, FIG. 2C is a cross-sectional view of FIG. 2A, taken along line I-I', FIG. 2D is a cross-sectional view of FIG. 2A, taken along line II-II', FIG. 2E is an enlarged view of portion "A" in FIG. 2A.

Referring to FIGS. 2A to 2E, the fingerprint sensor package **10** may include a first substrate **100**, a second substrate **200**, a controller chip **310**, a passive element **320**, a conductive support **340**, and a molding layer **350**.

A fingerprint sensor package **10** according to an embodiment may have a total thickness of about 0.76 mm or less. In some embodiments, the total thickness of the fingerprint sensor package **10** may be less than or equal to about 0.5 mm. For example, the total thickness of the fingerprint sensor package **10** may range from about 0.1 mm to about 0.4 mm or from 0.1 mm to 0.4 mm. Therefore, the fingerprint sensor package **10** may be easily applied to various products (e.g., the smart card described above) that may be bent or may require a thin thickness.

The first substrate **100** may include a core insulating layer **110**, first bonding pads **120**, external connection pads **130**, a ground bezel **150**, and an adhesive layer **160**. The first substrate **100** may include a printed circuit board (PCB). In example embodiments, the first substrate **100** may include a flexible PCB (FPCB) having flexibility to be bendable. In other example embodiments, the first substrate **100** may also include a rigid type PCB.

The core insulating layer **110** may have a substantially rectangular planar shape or a square planar shape, and may be provided as a flexible film or plate. The core insulating layer **110** may include a first surface **111** and a second surface **113**, opposite to each other. In this case, a direction, parallel to a pair of edges of the core insulating layer **110**, may be defined as a first direction (an X-direction), a direction, parallel to the other pair of edges of the core insulating layer **110**, may be defined as a second direction (a Y-direction), and a direction, perpendicular to a main surface (the first surface **111** or the second surface **113**) of the core insulating layer **110**, may be defined as a third direction (a Z-direction).

The core insulating layer **110** may include an insulating material. For example, the core insulating layer **110** may be a flexible film including polyimide. For example, the core insulation layer **110** may be formed of an epoxy resin, or a synthetic resin such as acrylic, polyether nitrile, polyether sulfone, polyethylene terephthalate, polyethylene naphthalate, or the like.

A through-hole **110H** penetrating through the first surface **111** and the second surface **113** may be formed in approximately a central portion of the core insulating layer **110**. The second substrate **200** may be accommodated in the through-hole **110H**, and the through-hole **110H** may be formed to be larger than the second substrate **200** such that a sidewall of the through-hole **110H** and a sidewall of the second substrate **200** do not come into contact with each other or are spaced apart from each other. In example embodiments, a first distance D1 between the sidewall of the through-hole **110H** and the sidewall of the second substrate **200** may range from about 0.1 mm to about 3.0 mm. The through-hole **110H** may be formed to have a substantially rectangular or square shape. The core insulating layer **110** may have a substantially rectangular or square ring shape.

Referring to FIGS. 2A and 2C, the first bonding pads **120** may be disposed around the through-hole **110H** on the second surface **113** of the core insulating layer **110**. For example, the first bonding pads **120** may be arranged along at least a portion of edges of the through-hole **110H** of the core insulating layer **110**. The first bonding pads **120** may be connected to the conductive support **340**, and may be electrically connected to second bonding pads **221B** of the second substrate **200** through the conductive support **340**.

The external connection pads **130** may be disposed on the second surface **113** of the core insulating layer **110**. The external connection pads **130** may be disposed adjacent to an edge of the second surface **113** of the core insulating layer **110**, and may be arranged along the edge of the second surface **113** of the core insulating layer **110**. The external connection pad **130** may be closer to the edge of the second surface **113** of the core insulating layer **110** than the first bonding pad **120**. For example, a distance between the edge of the second surface **113** of the core insulating layer **110** and the external connection pads **130** may be shorter than a distance between the edge of the second surface **113** of the core insulating layer **110** and the first bonding pad **120**. The external connection pads **130** may be pads electrically and physically connected to an external device (e.g., the card body **500** of FIG. 5G). The external connection pads **130** may be electrically connected to the first bonding pads **120** through a conductive pattern **114** provided on the second surface **113** of the core insulating layer **110**. An insulating layer **115** covering the conductive pattern **114** may be disposed on the second surface **113** of the core insulating layer **110**.

For example, the first bonding pads **120** and the external connection pads **130** may include at least one selected from copper (Cu), aluminum (Al), nickel (Ni), silver (Ag), gold (Au), platinum (Pt), tin (Sn), lead (Pb), titanium (Ti), chromium (Cr), palladium (Pd), indium (In), zinc (Zn), carbon (C), and alloys thereof.

Referring to FIGS. 2B and 2C, the ground bezel **150** may extend along a circumference of the through-hole **110H**. The ground bezel **150** may have a ring shape (e.g., rectangular or square ring shape) planarly surrounding the through-hole **110H**. The ground bezel **150** may be attached to the first surface **111** of the core insulating layer **110** by the adhesive layer **160**. When the through-hole **110H** is formed in a substantially central portion of the first surface **111** of the core insulating layer **110**, the ground bezel **150** may be disposed in an outer portion of the first surface **111** of the core insulating layer **110**. The ground bezel **150** may be closer to an edge of the first surface **111** of the core insulating layer **110** than the first bonding pad **120**. For example, a horizontal distance between the edge of the first surface **111** of the core insulating layer **110** and the ground bezel **150** may be shorter than a horizontal distance between the edge of the first surface **111** of the core insulating layer **110** and the first bonding pad **120**. The ground bezel **150** may be disposed at the edge of the core insulating layer **110** to reduce sensing noise while a user's fingerprint contacts an upper surface of the second substrate **200** bonded to the first substrate **100**. For example, the ground bezel **150** may include a conductive material, for example, a metal material such as copper (Cu) or aluminum (Al). The ground bezel **150** may be electrically grounded. In example embodiments, the ground bezel **150** may be configured to receive a reference potential through a conductive via **170** penetrating through the core insulating layer **110** and the adhesive layer **160**. The conductive via **170** may be configured to electrically connect the ground bezel **150** and the external connection pad **130**, and may be used as an electrical path for transferring the reference potential to the ground bezel **150**.

In example embodiments, the first substrate **100** may have a shape in which all outer corners CN are rounded. In some embodiments, a curvature radius (or radius of curvature) of the outer corner CN of the first substrate **100** may range from about 0.1 mm to about 2 mm. For example, the curvature radius of the outer corner CN of the first substrate **100** may be about 1 mm. The reason why the outer corner CN of the

first substrate **100** has a rounded shape may be provided to effectively prevent a crack that may occur at the outer corner CN during a process of cutting a first panel substrate **100P** (see FIG. 5F) using a punching facility PM (see FIG. 5E).

The second substrate **200** may have a substantially rectangular planar shape or a substantially square planar shape. The second substrate **200** may include an upper surface **200U** and a lower surface **200B**, opposite to each other. The upper surface **200U** of the second substrate **200** may be a surface contacted for fingerprint recognition, and the lower surface **200B** of the second substrate **200** may be a surface on which components such as the controller chip **310** or the like are mounted. The second substrate **200** may be received in the through-hole **110H** of the first substrate **100**, and may be electrically connected to the first substrate **100** through the conductive support **340**. For example, the second bonding pads **221B** of the second substrate **200** may be bonded or connected to the first bonding pads **120** of the first substrate **100** through the conductive support **340**. A thickness of the second substrate **200** may be substantially the same as a thickness of the first substrate **100**. Therefore, when the second substrate **200** is accommodated in the through-hole **110H** of the first substrate **100**, the upper surface **200U** of the second substrate **200** may be substantially coplanar with an upper surface **100U** of the first substrate **100**. However, the inventive concept is not limited thereto, and a thickness of the second substrate **200** may be thicker than a thickness of the first substrate **100**. A first length LX of the second substrate **200** in the first direction (the X-direction) may range from about 10 mm to about 15 mm. In addition, a second length LY of the second substrate **200** in the second direction (the Y-direction) may range about 10 mm to about 15 mm. For example, the first length LX of the second substrate **200** may be about 12.7 mm, and the second length LY may be about 12.7 mm.

Referring to FIG. 2C, the second substrate **200** may include a base layer **211**, a lower insulating layer **213** on a lower surface of the base layer **211**, an upper insulating layer **215** on an upper surface of the base layer **211**, a lower protective layer **217** on a lower surface of the lower insulating layer **213** and an upper protective layer **219** on an upper surface of the upper insulating layer **215**.

The second substrate **200** may include a printed circuit board (PCB). In example embodiments, the second substrate **200** may include a rigid type printed circuit board.

In addition, the second substrate **200** may be a multilayer PCB including a plurality of conductive layers. The second substrate **200** may include conductive layers located at different vertical levels, and conductive vias for electrically connecting the conductive layers to each other. The conductive layers and the conductive vias may include at least one selected from copper (Cu), aluminum (Al), nickel (Ni), silver (Ag), gold (Au), platinum (Pt), tin (Sn), lead (Pb), titanium (Ti), chromium (Cr), palladium (Pd), indium (In), zinc (Zn), carbon (C), and alloys thereof.

For example, the second substrate **200** may include first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P**, second conductive layers **223G**, **223R**, and **223T**, third conductive layers **225G**, **225R**, and **225T**, and fourth conductive layers **227G** and **227T**, in order of farther distance from the upper surface **200U**. The first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P** may be on the lower surface of the lower insulating layer **213**, the second conductive layers **223G**, **223R**, and **223T** may be on the lower surface of the base layer **211**, the third conductive layers **225G**, **225R**, and **225T** may be on the upper surface of the

base layer 211, and the fourth conductive layers 227G and 227T may be on the upper surface of the upper insulating layer 215.

The first conductive layers 221B, 221G, 221R, 221T, and 221P may include second bonding pads 221B, 1-1 sensing pads 221R, 1-2 sensing pads 221T, a first ground pattern 221G, and a power pattern 221P. The second conductive layers 223G, 223R, and 223T may include 2-1 sensing pads 223R, 2-2 sensing pads 223T, and a second ground pattern 223G. The third conductive layers 225G, 225R, and 225T may include first sensing patterns 225R, 3-2 sensing pads 225T, and a third ground pattern 225G. The fourth conductive layers 227G and 227T may include second sensing patterns 227T and a fourth ground pattern 227G.

In addition, the second substrate 200 may include first conductive vias 231G, 231R, and 231T for electrically connecting the first conductive layers 221B, 221G, 221R, 221T, and 221P and the second conductive layers 223G, 223R, and 223T, second conductive vias 233G, 233R, and 233T and third conductive vias 235G, 235R, and 235T, for electrically connecting the second conductive layers 223G, 223R, 223T and the third conductive layers 225G, 225R, and 225T, and fourth conductive vias 237T and 237G for electrically connecting the third conductive layers 225G, 225R and 225T and the fourth conductive layers 227G and 227T. The first conductive vias 231G, 231R, and 231T may at least partially penetrate the lower insulating layer 213, the second conductive vias 233G, 233R, and 233T may partially penetrate the base layer 211, the third conductive vias 235G, 235R, and 235T may partially penetrate the base layer 211, and the fourth conductive vias 237T and 237G may at least partially penetrate the upper insulating layer 215.

The first conductive vias 231G, 231R, and 231T may include 1-1 sensing vias 231R for electrically connecting the 1-1 sensing pads 221R and the 2-1 sensing pads 223R, 1-2 sensing vias 231T for electrically connecting the 1-2 sensing pads 221T and the 2-2 sensing pads 223T, and a first ground via 231G for electrically connecting the first ground pattern 221G and the second ground pattern 223G. In example embodiments, the first conductive vias 231G, 231R, and 231T may have a tapered structure in which a horizontal width decreases toward the base layer 211.

The second conductive vias 233G, 233R, and 233T may include 2-1 sensing vias 233R for electrically connecting the 2-1 sensing pads 223R and the first sensing patterns 225R, 2-2 sensing vias 233T for electrically connecting the 2-2 sensing pads 223T and 3-2 sensing pads 225T, and a second ground via 233G for electrically connecting the second ground pattern 223G and the third ground pattern 225G. The third conductive vias 235G, 235R, and 235T may include 3-1 sensing vias 235R for electrically connecting the 2-1 sensing pads 223R and the first sensing patterns 225R, 3-2 sensing vias 235T for electrically connecting the 2-2 sensing pads 223T and the 3-2 sensing pads 225T, and a third ground via 235G for electrically connecting the second ground pattern 223G and the third ground pattern 225G.

The second conductive vias 233G, 233R, and 233T may be in contact with the second conductive layer 223G, 223R, and 223T, the third conductive vias 235G, 235R, and 235T may be in contact with the third conductive layer 225G, 225R and 225T, and the second conductive vias 233G, 233R, and 233T and the third conductive vias 235G, 235R and 235T may be in contact with each other. Specifically, the 2-1 sensing pads 223R and the first sensing patterns 225R may be electrically connected to each other by the 2-1 sensing vias 233R and the 3-1 sensing vias 235R, which may be vertically connected. The 2-2 sensing pads 223T and the

3-2 sensing pads 225T may be electrically connected to each other by 2-2 sensing vias 233T and the 3-2 sensing vias 235T, which may be vertically connected, and the second ground pattern 223G and the third ground pattern 225G may be electrically connected to each other by the second ground via 233G and the third ground via 235G, which may be vertically connected.

In example embodiments, each of the second conductive vias 233G, 233R, and 233T and the third conductive vias 235G, 235R, and 235T may have a tapered structure in which a horizontal width decreases toward a center in a thickness direction of the base layer 211. In some embodiments, the second conductive vias 233G, 233R, and 233T and the third conductive vias 235G, 235R, and 235T may have a minimum horizontal width on a contact surface therebetween.

The fourth conductive vias 237T and 237G may include 4-2 sensing vias 237T for electrically connecting the 3-2 sensing pads 225T and the second sensing patterns 227T, and a fourth ground via 237G for electrically connecting the third ground pattern 225G and the fourth ground pattern 227G. In example embodiments, the fourth conductive vias 237T and 237G may have a tapered structure in which a horizontal width decreases toward the base layer 211.

Referring to FIG. 2A, the second substrate 200 may include a sensing region SR, a first contact region CR1, a second contact region CR2, a third contact region CR3, a wiring region YR, and a peripheral region ER. Specifically, the sensing region SR may be a region in which the first and second sensing patterns 225R and 227T for fingerprint recognition are disposed. Referring to FIG. 2C, the first contact region CR1 and the third contact region CR3 may be regions in which the 1-1 sensing vias 231R, the 2-1 sensing vias 233R, and the 3-1 sensing vias 235R, for connecting the first sensing patterns 225R and the controller chip 310, are disposed. Referring to FIG. 2D, the second contact region CR2 may be a region in which the 1-2 sensing vias 231T, the 2-2 sensing vias 233T, the 3-2 sensing vias 235T, and the 4-2 sensing vias 237T, for connecting the second sensing patterns 227T and the controller chip 310, may be disposed. The wiring region YR may be a region in which at least a portion of the first to fourth ground vias 231G, 233G, 235G, and 237G for connecting the fourth ground pattern 227G and the controller chip 310 are disposed.

Referring to FIGS. 2A and 2E, the sensing region SR may be disposed in a central portion of the second substrate 200. In some embodiments, the sensing region SR may have a rectangular or square shape, when viewed from a plan view. A plurality of first sensing patterns 225R, having a linear shape, spaced apart in the first direction (the X-direction), and extending in the second direction (the Y-direction), and a plurality of second sensing patterns 227T, having a linear shape, spaced apart in the second direction (the Y-direction), extending in the first direction (the X-direction), may be disposed in the sensing region SR.

The first contact region CR1 may be formed on one end or side of the sensing region SR in the second direction (the Y-direction), and the third contact region CR3 may be formed on the other end or side of the sensing region SR in the second direction (the Y-direction). In addition, the second contact region CR2 may be formed on one end or side of the sensing region SR in the first direction (the X-direction), and the wiring region YR may be formed on the other end or side of the sensing region SR in the first direction (the X-direction).

The peripheral region ER may be disposed in an outer portion of the second substrate 200. The peripheral region

ER may surround the sensing region SR in a plan view. The second bonding pads **221B** may be disposed in the peripheral region ER. In the peripheral region ER, the first to fourth ground patterns **221G**, **223G**, **225G**, and **227G** for providing a reference potential and shielding sensing noise may be at least partially disposed.

The first sensing patterns **225R** may extend between the sensing region SR and the first contact region CR1 or between the sensing region SR and the third contact region CR3. The first sensing patterns **225R** may be connected to the controller chip **310** through the 1-1 sensing vias **231R**, the 2-1 sensing vias **233R**, and the 3-1 sensing vias **235R**, disposed in the first and third contact regions CR1 and CR3. In the first contact region CR1, each of the 1-1 sensing vias **231R**, the 2-1 sensing vias **233R**, and the 3-1 sensing vias **235R** may be arranged in the first direction (the X-direction). In addition, in the third contact region CR3, each of the 1-1 sensing vias **231R**, the 2-1 sensing vias **233R**, and the 3-1 sensing vias **235R** may be arranged in the first direction (the X-direction). Some of the first sensing patterns **225R** may be connected to the 1-1 sensing vias **231R**, the 2-1 sensing vias **233R**, and the 3-1 sensing vias **235R**, disposed in the first contact region CR1. In addition, other portions of the first sensing patterns **225R** may be connected to the 1-1 sensing vias **231R**, the 2-1 sensing vias **233R**, and the 3-1 sensing vias **235R**, disposed in the third contact region CR3. Neighboring first sensing patterns **225R** may be electrically separated.

The second sensing patterns **227T** may extend within the sensing region SR and the second contact region CR2. The second sensing patterns **227T** may be connected to the controller chip **310** through the 1-2 sensing vias **231T**, the 2-2 sensing vias **233T**, the 3-2 sensing vias **235T**, and the 4-2 sensing vias **237T**, disposed in the second contact region CR2. Each of the 1-2 sensing vias **231T**, the 2-2 sensing vias **233T**, the 3-2 sensing vias **235T**, and the 4-2 sensing vias **237T** may be arranged staggered in a zigzag pattern in the second direction (the Y-direction).

The first sensing patterns **225R** may have a first width W1 in the first direction (the X-direction), and the second sensing patterns **227T** may have a second width W2 in the second direction (the Y-direction). In some embodiments, the first width W1 may be wider than the second width W2. For example, the first width W1 may have a range of about 2 times to about 4 times the second width W2. Specifically, the first width W1 may have a range of about 40 μm to about 70 μm , and the second width W2 may have a range of about 5 μm to about 25 μm .

A portion in which the first sensing patterns **225R** and the second sensing patterns **227T** overlap in the third direction (the Z-direction) may constitute pixels PX. A first pitch or spacing PIX in the first direction (the X-direction) between centers PXC of the pixels PX may be substantially the same as a second pitch or spacing PIY in the second direction (the Y-direction) between the centers PXC of the pixels PX, but is not limited thereto. For example, each of the first pitch PIX and the second pitch PIY may have a range of about 50 μm to about 90 μm .

The pixels PX may have a composite capacitance value of area capacitance AC by the first sensing patterns **225R** and the second sensing patterns **227T**, overlapping each other, and fringing capacitance by the first sensing patterns **225R** and the second sensing patterns **227T**.

When the user's fingerprint comes into contact with the upper surface **200U** of the second substrate **200**, a capacitance value corresponding to each of the pixels PX may be changed by capacitance induced between the second sensing

patterns **227T** and the user's fingerprint. Since the change in capacitance value is determined according to a shape of the user's fingerprint, the controller chip **310** may identify the user's fingerprint from the change in capacitance value of the pixels PX.

The fourth ground pattern **227G** may planarly surround the sensing region SR on which the second sensing patterns **227T** is disposed. The fourth ground pattern **227G** may be located on the same vertical level as the second sensing patterns **227T**, and may planarly surround the second sensing patterns **227T**. For example, the fourth ground pattern **227G** may continuously extend along an edge of the sensing region SR on an upper surface of the upper insulating layer **215**, to planarly surround the second sensing patterns **227T**. The fourth ground pattern **227G** may be disposed around the sensing region SR while the user's fingerprint is in contact with the sensing region SR, to reduce sensing noise.

The base layer **211** may include an insulating material. The base layer **211** may include a resin and a glass fiber. The resin included in the base layer **211** may be at least one selected from a phenol resin, an epoxy resin, and polyimide. In some embodiments, the base layer **211** may include at least one material selected from flame retardant 4 (FR4), tetrafunctional epoxy, polyphenylene ether, epoxy/polyphe-nylene oxide, a thermount, bismaleimide triazine (BT), cyanate ester, polyimide, a prepreg, an Ajinomoto build-up film (ABF), and a liquid crystal polymer. In other embodiments, the base layer **211** may include silicon oxide, silicon nitride, silicon oxynitride, or a combination thereof. The glass fiber included in the base layer **211** may be a reinforcing material, and may be a glass filament obtained by melt-spinning a glass material at a high temperature and then treating the same by a convergence process. The glass filament may be a processed ore product containing silica as a main component.

Hereinafter, for convenience of description and understanding, components of the second substrate **200** will be described in order of closer distance to the base layer **211**.

The second conductive layers **223G**, **223R**, and **223T** may include 2-1 sensing pads **223R**, 2-2 sensing pads **223T**, and a second ground pattern **223G** to which a reference potential is applied. The second ground pattern **223G** may be disposed in the sensing region SR, the wiring region YR, and the peripheral region ER. A portion of the second ground pattern **223G** may overlap the first sensing patterns **225R** and the second sensing patterns **227T** in the third direction (the Z-direction). A portion of the second ground pattern **223G** may be interposed between the second sensing patterns **227T** and the controller chip **310**. Therefore, the second ground pattern **223G** may block external sensing noise from the controller chip **310**. The 2-1 sensing pads **223R** may be disposed on the first and third contact regions CR1 and CR3, and the 2-2 sensing pads **223T** may be disposed on the second contact region CR2. The 2-1 sensing pads **223R** may provide a path for electrical connection between the first sensing patterns **225R** and the controller chip **310**, and the 2-2 sensing pads **223T** may provide a path for electrical connection between the second sensing patterns **227T** and the controller chip **310**.

The lower insulating layer **213** may be disposed on the lower surface of the base layer **211** to at least partially cover or surround the second conductive layers **223G**, **223R**, and **223T**. The lower insulating layer **213** may electrically separate the 2-1 sensing pads **223R**, the 2-2 sensing pads **223T**, and the second ground pattern **223G** from each other.

The third conductive layers **225G**, **225R**, and **225T** may include a third ground pattern **225G** to which a reference

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potential is applied, first sensing patterns **225R** for recognizing a user's fingerprint, and 3-2 sensing pads **225T**. The first sensing patterns **225R** may be disposed in the sensing region SR, the third ground pattern **225G** may be disposed in the wiring region YR and the peripheral region ER, and the 3-2 sensing pads **225T** may be disposed in the second contact region CR2. The 3-2 sensing pads **225T** may provide a path for electrical connection between the second sensing patterns **227T** and the controller chip **310**.

The upper insulating layer **215** may be disposed on the upper surface of the base layer **211** to at least partially cover or surround the third conductive layers **225G**, **225R**, and **225T**. The upper insulating layer **215** may electrically separate the first sensing patterns **225R**, the 3-2 sensing pads **225T**, and the third ground pattern **225G** from each other.

The lower insulating layer **213** and the upper insulating layer **215** may include different materials. For example, the upper insulating layer **215** may include a material having a permittivity suitable for fingerprint recognition of the fingerprint sensor package **10**. However, the materials of the lower insulating layer **213** and the upper insulating layer **215** are not limited thereto, and the lower insulating layer **213** and the upper insulating layer **215** may include the same material.

Each of the lower insulating layer **213** and the upper insulating layer **215** may include at least one selected from a phenol resin, an epoxy resin, and polyimide. In some embodiments, each of the lower insulating layer **213** and the upper insulating layer **215** may include at least one selected from a prepreg, FR4, tetragonal epoxy, polyphenylene ether, epoxy/polyphenylene oxide, a thermount, BT, cyanate ester, polyimide, and a liquid crystal polymer.

The fourth conductive layers **227G** and **227T** may be disposed on the upper surface of the upper insulating layer **215**. The fourth conductive layers **227G** and **227T** may include a fourth ground pattern **227G** for removing sensing noise and second sensing patterns **227T** for recognizing a user's fingerprint. The second sensing patterns **227T** may be disposed in the sensing region SR, and the fourth ground pattern **227G** may be disposed in the peripheral region ER.

The second sensing patterns **227T** may be spaced apart from the first sensing patterns **225R** in the third direction (the Z-direction), with the upper insulating layer **215** interposed therebetween. For example, the second sensing patterns **227T** may be electrically insulated from the first sensing patterns **225R** by the upper insulating layer **215**. Therefore, the first sensing patterns **225R** may constitute a first electrode of a capacitor, the upper insulating layer **215** may constitute a dielectric layer of the capacitor, and the second sensing patterns **227T** may constitute a second electrode of the capacitor. For example, capacitors constituting the fingerprint sensor may be formed in the second substrate **200**.

The upper protective layer **219** may be disposed on the upper surface of the upper insulating layer **215** to cover the fourth conductive layers **227G** and **227T**.

The first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P** may be disposed on the lower surface of the lower insulating layer **213**. The first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P** may include second bonding pads **221B**, 1-1 sensing pads **221R**, 1-2 sensing pads **221T**, a power pattern **221P**, and a first ground pattern **221G** to which a reference potential is applied.

The second bonding pads **221B** may be directly or indirectly bonded and electrically connected to the first bonding pads **120** of the first substrate **100**. For example, the second bonding pads **221B** may include at least one selected from

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tin (Sn), gold (Au), and alloys thereof. The second bonding pads **221B** may be formed at positions corresponding to the first bonding pads **120** and in sizes corresponding to each other. The second bonding pads **221B** may include a power pad to which power (e.g., power supply potential) provided from an external device is applied, ground pads to which reference potential is applied, and an output pad for outputting a fingerprint recognition result of the fingerprint sensor package **10** externally (e.g., to the display unit **12** of the smart card **1** of FIG. 1). The controller chip **310** may receive power potential through some of the second bonding pads **221B** and the power pattern **221P**, and may receive reference potential through some of the second bonding pads **221B** and the first ground pattern **221G**. In addition, the controller chip **310** may receive a signal recognized by the first and second sensing patterns **225R** and **227T** through the 1-1 sensing pads **221R** and the 1-2 sensing pads **221T**.

The 1-1 sensing pads **221R** may extend from the first and third contact regions CR1 and CR3 to a portion overlapping the controller chip **310** in the third direction (the Z-direction), and the 1-2 sensing pads **221T** may extend from the second contact region CR2 to a portion overlapping the controller chip **310** in the third direction (the Z-direction). The 1-1 sensing pads **221R** may provide a path for electrical connection between the first sensing patterns **225R** and the controller chip **310**, and the 1-2 sensing pads **221T** may provide a path for electrical connection between the second sensing patterns **227T** and the controller chip **310**.

The lower protective layer **217** may be disposed on the lower surface of the lower insulating layer **213** to cover or surround at least a portion of the first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P**. In some example embodiments, the lower protective layer **217** may be formed to cover a region of the lower surface of the lower insulating layer **213**. In other example embodiments, the lower protective layer **217** may be formed to entirely cover the lower surface of the lower insulating layer **213**.

Each of the lower protective layer **217** and the upper protective layer **219** may be an insulating coating layer. In some embodiments, the lower protective layer **217** and the upper protective layer **219** may be formed as a solder resist. In other embodiments, the lower protective layer **217** and the upper protective layer **219** may include a polymer material having excellent heat resistance, insulation, and hardness. For example, each of the lower protective layer **217** and the upper protective layer **219** may be formed of polyimide, polyamide, polyacetal, polycarbonate, or the like. In some embodiments, the upper protective layer **219** may include a material having permittivity suitable for fingerprint recognition (e.g., a high dielectric material).

Referring to FIGS. 2A and 2C, the conductive support **340** may electrically connect the first bonding pads **120** of the first substrate **100** and the second bonding pads **221B** of the second substrate **200** to each other, and may support the first substrate **100** and the second substrate **200**, spaced apart from each other, from below to maintain electrical connection of the first substrate **100** and the second substrate **200**, even when an external force is applied to the upper surface **200U** of the second substrate **200**.

The conductive support **340** may have a predetermined thickness and a predetermined width, and may be formed to have a rectangular shape elongated in one direction. However, the inventive concept is not limited thereto, and the conductive support **340** may be modified to have various shapes. For example, when the first bonding pads **120** and the second bonding pads **221B** may be located on the same vertical level, the conductive support **340** may be formed to

have a bar shape. When the first bonding pads **120** and the second bonding pads **221B** are located on different vertical levels, in the conductive support **340**, one portion thereof may be formed to be thicker than a thickness of any other portion thereof to compensate for a difference in vertical levels. In addition, when viewed from the top, a portion of the conductive support **340** may have a wider width than any other portion of the conductive support **340**.

The conductive support **340** may include a material having high electrical conductivity. For example, the conductive support **340** may include a metal material such as copper (Cu) or aluminum (Al). In addition, the conductive support **340** may maintain an original shape thereof even when an external force is applied, and may firmly support the first substrate **100** and the second substrate **200**. To this end, the conductive support **340** may be formed of a material having high rigidity.

The conductive support **340** may be bonded to the first bonding pads **120** and the second bonding pads **221B** through a conductive member **342**. For example, the conductive member **342** may be a solder bump, but is not limited thereto, and, for example, a conductive epoxy such as silver epoxy or an anisotropic conductive film (ACF) may be used as the conductive member **342**. A groove **341** may be formed on an upper surface of the conductive support **340** to limit a position to which the conductive member **342** is attached.

The controller chip **310** and the passive element **320** may be disposed on the lower surface **200B** of the second substrate **200**. The controller chip **310** may be mounted on the lower surface **200B** of the second substrate **200** in a flip chip manner. Connection bumps **315** for electrically and physically connecting the controller chip **310** and the second substrate **200** may be disposed between the controller chip **310** and the second substrate **200**. The connection bumps **315** may be disposed between some patterns of the first conductive layers **221B**, **221G**, **221R**, **221T**, and **221P** and chip pads **311** of the controller chip **310**.

In some embodiments, the controller chip **310** may be entirely or partially disposed within the sensing region **SR**. In other embodiments, the controller chip **310** may be entirely disposed outside the sensing region **SR**. The controller chip **310** may include any component configured to perform an operation for recognizing a user's fingerprint from changes in capacitance values of the pixels **PX**, such as a memory chip and/or a processor chip. In addition, the passive element **320** may include, for example, a multilayer ceramic capacitor (MLCC), but is not limited thereto.

The molding layer **350** may be disposed on the first substrate **100** and the second substrate **200** to cover the controller chip **310**, the conductive support **340**, and the passive element **320**. The molding layer **350** may be in or fill a space between the sidewall of the through-hole **110H** and the sidewall of the second substrate **200**. The molding layer **350** may serve to protect the second substrate **200**, the controller chip **310**, and the passive element **320** from external influences such as contamination, impact, or the like. An upper surface **350U** of the molding layer **350** may be formed to be substantially coplanar with the upper surface **100U** of the first substrate **100** and the upper surface **200U** of the second substrate **200**. However, the inventive concept is not limited thereto, and according to embodiments, the upper surface **350U** of the molding layer **350** may be formed concavely due to a meniscus generated during a manufacturing process. The molding layer **350** may have a

central portion thicker than edges. For example, a lower surface **350B** of the molding layer **350** may be formed to be convex.

In addition, the molding layer **350** may at least partially cover or surround the first bonding pads **120** disposed on the second surface **113** of the core insulating layer **110**, but may not cover the external connection pads **130** to be exposed externally. The molding layer **350** may be extended along a boundary between a region in which the first bonding pads **120** are disposed and a region in which the external connection pads **130** are disposed, on the second surface **113** of the core insulating layer **110**. The molding layer **350** may extend laterally from a side surface of the second substrate **200** to at least partially cover or surround the first bonding pad **120**, but may be spaced apart from the external connection pads **130**. The molding layer **350** may be formed to cover a second distance **D2** from the through-hole **110H** of the first substrate **100**. For example, the second distance **D2** may have a range of about 0.1 mm to about 3.0 mm.

The molding layer **350** may be formed of an epoxy molding compound. Alternatively, the molding layer **350** may be formed of an epoxy-based material, a thermosetting material, a thermoplastic material, a UV treated material, or the like.

In a fingerprint sensor package **10** according to an embodiment, the first bonding pads **120** of the first substrate **100** may be connected to the second bonding pads **221B** of the second substrate **200** by the conductive support **340**. Therefore, compared to a case in which the first bonding pads **120** and the second bonding pads **221B** are connected using a conductive wire, even when mechanical stress is repeatedly applied to the second substrate **200**, electrical connection between the first substrate **100** and the second substrate **200** may not be damaged. Therefore, reliability of the fingerprint sensor package **10** may be improved.

FIGS. **3A** to **3C** are views illustrating a fingerprint sensor package according to an embodiment. Specifically, FIG. **3A** is a bottom view schematically illustrating a layout of some components of a fingerprint sensor package **20**, FIG. **3B** is a cross-sectional view of FIG. **3A**, taken along line III-III', and FIG. **3C** is an enlarged view of portion "B" in FIG. **3B**.

A fingerprint sensor package **20** illustrated in FIGS. **3A** to **3C** may be substantially the same as or similar to the fingerprint sensor package **10** described with reference to FIGS. **2A** to **2E**, except that a conductive support **340A** has a bent shape and a dummy support **340D** is further included. Hereinafter, a fingerprint sensor package **20** according to an embodiment will be described, focusing on differences from the fingerprint sensor package **10** described with reference to FIGS. **2A** to **2E**.

Referring to FIG. **3A**, a fingerprint sensor package **20** according to an example embodiment may further include a dummy support **340D** connecting a first substrate **100** and a second substrate **200** to each other.

The dummy support **340D** may be disposed around a conductive support **340A** to connect the first substrate **100** and the second substrate **200** to each other. The dummy support **340D** may support the first substrate **100** and the second substrate **200** more firmly by supporting the first substrate **100** and the second substrate **200** spaced apart from each other from below. Depending on an embodiment, when viewed from the bottom, an area of the dummy support **340D** may be formed to be larger than an area of the conductive support **340A**, to more firmly support the first substrate **100** and the second substrate **200**.

The dummy support **340D** may be disposed to overlap the first substrate **100** at or in each outer corner region of the

second substrate **200**. The dummy support **340D** may be attached to connect first dummy bonding pads **120D** of the first substrate **100** and second dummy bonding pads **221BD** of the second substrate **200**. Depending on an embodiment, at least one of the first dummy bonding pads **120D** and at least one of the second dummy bonding pads **221BD** may be electrically grounded.

The dummy support **340D** may be formed of a material having high rigidity. The dummy support **340D** may be formed of the same material as the conductive support **340A**, but depending on embodiments, the dummy support **340D** may be formed of a material different from that of the conductive support **340A**. Depending on an example embodiment, the dummy support **340D** may be formed of a material having high rigidity or not having high electrical conductivity.

Referring to FIGS. **3B** and **3C**, a conductive support **340A** of an embodiment may have a bent shape when viewed from the side. The conductive support **340A** may have first to third regions **340A1**, **340A2**, and **340A3** to compensate for a difference in vertical level between first bonding pads **120** and second bonding pads **221B**. The first region **340A1** and the second region **340A2** may be disposed on a vertical level capable of being connected to the first bonding pads **120** and the second bonding pads **221B** through a conductive member **342**, respectively. The third region **340A3** may be inclined and may be between or connect the first and second regions **340A1**, **340A2**.

FIG. **4** is a cross-sectional view illustrating a modified example of the conductive support **340A** illustrated in FIG. **3C**. The conductive support **340A** of FIG. **3C** described above may be bent to compensate for the difference in vertical level between the first bonding pads **120** and the second bonding pads **221B**. In a conductive support **340B** of FIG. **4**, one portion thereof may be formed to be thicker than a remaining portion thereof, to compensate for a difference in vertical level between first bonding pads **120** and second bonding pads **221B**. For example, in the conductive support **340B**, a thickness **T1** of a region corresponding to the first bonding pads **120** may be thicker than a thickness **T2** of a region corresponding to the second bonding pads **221B**.

FIGS. **5A** to **5H** are views illustrating a method of manufacturing a smart card in a process sequence according to an embodiment. Specifically, FIGS. **5A** to **5F** are processes for manufacturing a fingerprint sensor package mounted on a smart card, and FIGS. **5G** and **5H** are processes for manufacturing a smart card by mounting the fingerprint sensor package on a card body.

Referring to FIG. **5A**, a second substrate **200** may be prepared, and a controller chip **310** and a passive element **320** may be mounted on the second substrate **200**. The controller chip **310** may be mounted on the second substrate **200** using a flip chip method.

Referring to FIG. **5B**, a first panel substrate **100P** on which the second substrate **200** is to be mounted may be prepared. Most of the components and materials constituting the first panel substrate **100P** may be substantially the same as or similar to those of the first substrate **100** of the fingerprint sensor package **10** described above with reference to FIGS. **2A** to **2E**. The first panel substrate **100P** may have a larger planar area than the first substrate **100** such that a plurality of second substrates **200** are mounted thereon. The first panel substrate **100P** may be mounted on a winding reel facility, and reeling and releasing of the first panel substrate **100P** may be controlled by the winding reel facility. The first panel substrate **100P** may be provided in a state in which a through-hole **110H** is formed and a carrier

tape **CT** is attached to a rear surface. The carrier tape **CT** may be for temporarily fixing the second substrate **200** in a subsequent process.

Referring to FIG. **5C**, the second substrate **200** may be disposed in the through-hole **110H** of the first panel substrate **100P**. The second substrate **200** may be fixed in the through-hole **110H** by being attached to the carrier tape **CT** exposed on a lower surface of the through-hole **110H** of the first panel substrate **100P**. After disposing the second substrate **200** in the through-hole **110H** of the first panel substrate **100P**, a conductive support **340** for electrically connecting the first panel substrate **100P** and the second substrate **200** may be attached. The conductive support **340** may be connected to a first bonding pad **120** of the first panel substrate **100P** and a second bonding pad **221B** of the second substrate **200** through a conductive member **342**.

Referring to FIG. **5D**, a molding layer **350** may be formed on a second surface **113** of a core insulating layer **110**. The molding layer **350** may at least partially cover the first panel substrate **100P**, the controller chip **310**, the conductive support **340**, and the passive element **320**. The molding layer **350** may be configured to flow into the through-hole **110H** of the first panel substrate **100P** and at least partially cover a side surface of the through-hole **110H** and an upper surface of the second substrate **200**. Also, the molding layer **350** may be formed not to cover an external connection pad **130** of the first panel substrate **100P**.

Referring to FIG. **5E**, the carrier tape **CT** may be removed from the first panel substrate **100P**.

Referring to FIG. **5F**, the first panel substrate **100P** may be cut using a punching facility or punching mechanism **PM**. The punching facility **PM** may cut the first panel substrate **100P** to form a fingerprint sensor package **10**, as described in FIGS. **2A** to **2E**. As the first panel substrate **100P** is cut, a plurality of first substrates **100** (FIG. **2C**) may be formed from the first panel substrate **100P**. To efficiently prevent cracks that may occur in a process of cutting the first panel substrate **100P** using the punching facility **PM**, the punching facility **PM** may cut the first panel substrate **100P** to have a shape in which corners of each of the first substrates **100** are rounded.

Referring to FIG. **5G**, a card body **500** including a card substrate **520**, a connection pad **530**, and a security chip **11** may be prepared.

The card body **500** may include a groove region or recess **510** for mounting the fingerprint sensor package **10** thereon. The card substrate **520** and the security chip **11** for storing financial information may be disposed on the card body **500**. For example, **FPCB** may be used as the card substrate **520**. The security chip **11** may be mounted on the card substrate **520**. The security chip **11** may be disposed within the card body **500** such that one surface thereof may be exposed externally. In addition, the connection pad **530** for electrical connection between the fingerprint sensor package **10** and other components in the card body **500** may be disposed on the card substrate **520**. The connection pad **530** may include a conductive material. The fingerprint sensor package **10** may be aligned with the groove region **510** of the card body **500** such that an upper surface **200U** of the second substrate **200** is exposed externally.

Referring to FIG. **5H**, the fingerprint sensor package **10** may be mounted on the card body **500**. A portion of the fingerprint sensor package **10** may be accommodated in the groove region **510** of the card body **500**. The molding layer **350** of the fingerprint sensor package **10** may be accommodated in the groove region **510**, and the external connection pad **130** of the first substrate **100** may be bonded to the

connection pad **530** of the card substrate **520**. The external connection pads **130** of the first substrate **100** may be physically and electrically connected to the connection pads **530** of the card substrate **520**. In some embodiments, the groove region **510** may not be completely filled by the molding layer **350** of the fingerprint sensor package **10**, and a flow space **S** between the molding layer **350** of the fingerprint sensor package **10** and the card body **500** may be formed. The flow space **S** may provide a space in which the fingerprint sensor package **10** flexibly responds to a degree of curvature of the smart card **1**. In other embodiments, the flow space **S** may be filled by applying an adhesive.

Referring back to FIG. 1, the smart card **1** may include a fingerprint sensor package **10**, a security chip **11**, a display unit **12**, and a power button **13**. When a user touches a fingerprint to the fingerprint sensor package **10** of the smart card **1**, a contacted fingerprint may be recognized. When a recognized fingerprint and a registered fingerprint match, the security chip **11** may grant payment authority to the user of the smart card **1**.

A fingerprint sensor package according to an embodiment may have improved reliability, and may provide performance, not being damaged even after repeated use. In addition, the smart card according to an embodiment may have improved reliability, and may provide performance, not being damaged even after repeated use.

Various advantages and effects of the present inventive concept are not limited to the above description, and will be more easily understood in the process of describing specific embodiments of the present inventive concept.

While example embodiments have been illustrated and described above, it will be apparent to those skilled in the art that modifications and variations could be made without departing from the scope of the present inventive concept as defined by the appended claims.

What is claimed is:

1. A fingerprint sensor package comprising:

a first substrate including a core insulating layer including a first surface and an opposite second surface and a through-hole extending through the first and second surfaces, a first bonding pad disposed along a circumference of the through-hole on the second surface of the core insulating layer, and an external connection pad between an edge of the second surface of the core insulating layer and the first bonding pad;

a second substrate in the through-hole of the core insulating layer and including a third surface and an opposite fourth surface, the second substrate including a plurality of first sensing patterns on the third surface, spaced apart in a first direction and extending in a second direction intersecting the first direction, a plurality of second sensing patterns spaced apart from each other in the second direction and extending in the first direction, and a second bonding pad on the fourth surface;

a conductive support vertically overlapping the first substrate and the second substrate, supporting the first substrate and the second substrate below the first substrate and the second substrate, and electrically connecting the first bonding pad and the second bonding pad to each other;

a controller chip on the second substrate; and

a molding layer on the second surface of the core insulating layer, at least partially filling the through-hole between the first substrate and the second substrate,

covering at least a portion of the second substrate and the first bonding pad, and spaced apart from the external connection pad.

2. The fingerprint sensor package of claim **1**, wherein the conductive support is connected to each of the first bonding pad and the second bonding pad by a conductive member.

3. The fingerprint sensor package of claim **2**, wherein the conductive member comprises at least one of a solder bump, silver epoxy, or an anisotropic conductive film (ACF).

4. The fingerprint sensor package of claim **2**, wherein the conductive support has a groove portion on a surface contacting the conductive member to limit a position at which the conductive member is attached.

5. The fingerprint sensor package of claim **1**, wherein the conductive support has a rectangular bar shape.

6. The fingerprint sensor package of claim **1**, further comprising a dummy support adjacent the conductive support and connecting the first substrate and the second substrate to each other.

7. The fingerprint sensor package of claim **6**, wherein the first substrate further comprises a first dummy bonding pad disposed along the circumference of the through-hole, the second substrate further comprises a second dummy bonding pad adjacent the second bonding pad, and the dummy support is formed of the same material as the conductive support.

8. The fingerprint sensor package of claim **7**, wherein at least one of the first dummy bonding pad and the second dummy bonding pad is electrically grounded.

9. The fingerprint sensor package of claim **7**, wherein the dummy support is formed of a material having higher rigidity than the conductive support.

10. The fingerprint sensor package of claim **7**, wherein the dummy support vertically overlaps the first substrate in each outer corner region of the second substrate.

11. The fingerprint sensor package of claim **7**, wherein an area of the dummy support is larger than an area of the conductive support.

12. The fingerprint sensor package of claim **1**, wherein the first substrate further comprises a ground bezel extending along a circumference of the through-hole on the first surface of the core insulating layer,

wherein a horizontal distance between an edge of the first surface of the core insulating layer and the ground bezel is shorter than a horizontal distance between the edge of the first surface of the core insulating layer and the first bonding pad.

13. The fingerprint sensor package of claim **1**, wherein the second substrate further comprises:

a base layer;
a lower insulating layer on a lower surface of the base layer; and
an upper insulating layer on an upper surface of the base layer,

wherein the plurality of first sensing patterns are on the upper surface of the base layer,

the plurality of second sensing patterns are on an upper surface of the upper insulating layer,

the second bonding pad and the controller chip are on a lower surface of the lower insulating layer.

14. The fingerprint sensor package of claim **13**, further comprising:

an upper protective layer covering the upper surface of the upper insulating layer; and

a lower protective layer covering the lower surface of the lower insulating layer.

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- 15. A fingerprint sensor package comprising:
 - a first substrate including a core insulating layer including a first surface and an opposite second surface, the first substrate including a through-hole, a first bonding pad extending along a circumference of the through-hole on the second surface, and an external connection pad on an edge of the second surface;
 - a second substrate including a third surface including a sensing region and a peripheral region surrounding the sensing region and a fourth surface opposite to the third surface, and including a second bonding pad extending along an edge of the fourth surface;
 - a conductive support vertically overlapping the first substrate and the second substrate, supporting the first substrate and the second substrate below the first substrate and the second substrate, and electrically connecting the first bonding pad and the second bonding pad to each other; and
 - a controller chip on the fourth surface.
- 16. The fingerprint sensor package of claim 15, wherein the conductive support is connected to each of the first bonding pad and the second bonding pad by a conductive member,
 - wherein the conductive member includes at least one of a solder bump, silver epoxy, and an anisotropic conductive film (ACF).
- 17. The fingerprint sensor package of claim 15, wherein the core insulating layer is a flexible film.
- 18. A smart card comprising:
 - a card body including a groove region and a contact pad;
 - a security chip in the card body; and
 - a fingerprint sensor package configured to sense a user's fingerprint and transmit a signal for a sensing result to the security chip,
 wherein the fingerprint sensor package includes:
 - a first substrate including a core insulating layer including a first surface and a second surface, opposite to each other, and having a substantially rectangular or square

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- ring shape with a through-hole passing through the first and second surfaces, a first bonding pad disposed along a circumference of the through-hole on the second surface of the core insulating layer, and an external connection pad between an edge of the second surface of the core insulating layer and the first bonding pad;
 - a second substrate in the through-hole of the core insulating layer and including a third surface and a fourth surface, opposite to each other, and including a plurality of first sensing patterns spaced apart in a first direction and extending in a second direction, perpendicular to the first direction, a plurality of second sensing patterns spaced apart from each other in the second direction and extending in the first direction, and a second bonding pad;
 - a conductive support vertically overlapping the first substrate and the second substrate, supporting the first substrate and the second substrate below the first substrate and the second substrate, and electrically connecting the first bonding pad and the second bonding pad to each other;
 - a controller chip on the second substrate; and
 - a molding layer on the second surface of the core insulating layer, filling the through-hole between the first substrate and the second substrate, at least partially covering the second substrate and the first bonding pad, and spaced apart from the external connection pad.
19. The smart card of claim 18, wherein the first surface of the first substrate is coplanar with the third surface of the second substrate.
20. The smart card of claim 18, wherein the first substrate is a flexible PCB (FPCB), and the second substrate is a rigid type printed circuit board (PCB).

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